

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249617US2S DIV		SERIAL NO. New DIV Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
<i>Re</i> <i>Re</i> <i>Re</i> <i>Re</i> <i>Re</i>	AA	5,440,631	08/1995	Akiyama, et al.			
	AB	5,771,334	06/1998	Yamauchi, et al.			
	AC	5,857,021	01/1999	Kataoka, et al.			
	AD	6,047,103	04/2000	Yamauchi, et al.			
	AE	6,088,312	07/2000	Utsumi, et al.			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
<i>Re</i> <i>Re</i> <i>Re</i>	AO	6-103317	04/15/94	Japan	x		
	AP	8-221948	08/30/1996	Japan (w/English Translation)	x		
	AQ	6-349248	12/1994	Japan			
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>Re</i> <i>Re</i> <i>Re</i>	AW	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD09805001					
	AX	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD00103788					
	AY	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD00103787					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>Robert Chal...</i>				Date Considered <i>6/11/05</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							